


<b>Search Notes</b>  	<b>Application/Control No.</b>  10534536	<b>Applicant(s)/Patent Under Reexamination</b>  FUKUSHIMA ET AL.
	<b>Examiner</b>  HENOK G HEYI	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Searched EAST and consulted with Primary Tan Dinh. Some of the subclasses searched are 369/275.1-4 and 428/64.1-4 (text search only - please see search history printout).	01/14/2009	HH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/HENOK G HEYI/ Examiner.Art Unit 2627	
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